## Notice of References Cited 10/720,173 Reexamination HAN, EUN-BONG Examiner Leonard S. Liang 2853 Reexamination HAN EUN-BONG Page 1 of 1

Application/Control No.

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,273,537	08-2001	Hiwada, Shuhei	347/10
*	В	US-2003/0001911	01-2003	Hirayama et al.	347/9
*	С	US-5,519,416	05-1996	Hayasaki et al.	347/13
*	D	US-6,116,714	09-2000	Imanaka et al.	347/19
*	E	US-6,382,755	05-2002	Imanaka et al.	347/12
*	F	US-6,471,324	10-2002	Maru, Hiroyuki	347/19
*	G	US-6,528,925	03-2003	Takeuchi et al.	310/316.03
*	н	US-6,844,658	01-2005	Hoshino, Takayuki	310/316.03
*	1	US-5,504,505	04-1996	Tamura et al.	347/13
*	J	US-5,975,670	11-1999	Kikuta et al.	347/15
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under